

Appendix C

Uncertainty Analysis

Uncertainty of SAR equipments for measurement

Items	Uncertainty value %	Probability Distribution	Divisor	ci 1 1g	Standard unc (1g)	vi or Veff
Measurement System						
Probe calibration	4.8	normal	1	1	4.8%	∞
Axial isotropy	4.7	rectangular	$\sqrt{3}$	$(1-c_p)^{1/2}$	1.9%	∞
Hemispherical isotropy	9.6	rectangular	$\sqrt{3}$	$(c_p)^{1/2}$	3.9%	∞
Boundary effects	1.0	rectangular	$\sqrt{3}$	1	0.6%	∞
Linearity	4.7	rectangular	$\sqrt{3}$	1	2.7%	∞
System Detection limits	1.0	rectangular	$\sqrt{3}$	1	0.6%	∞
Readout Electronics	1.0	normal	1	1	1.0%	∞
Response time	0.8	rectangular	$\sqrt{3}$	1	0.5%	∞
Integration time	2.6	rectangular	$\sqrt{3}$	1	1.5%	∞
RF Ambient Conditions	3.0	rectangular	$\sqrt{3}$	1	1.7%	∞
Mech. constrains of robot	0.4	rectangular	$\sqrt{3}$	1	0.2%	∞
Probe positioning	2.9	rectangular	$\sqrt{3}$	1	1.7%	∞
Extrap. and integration	1.0	rectangular	$\sqrt{3}$	1	0.6%	∞

Uncertainty of measurements

Test Sample Related						
Device positioning	2.9	normal	1	1	2.9%	145
Device holder uncertainty	3.6	normal	1	1	3.6%	5
Power drift	5.0	rectangular	$\sqrt{3}$	1	2.9%	∞
Phantom and Setup						
Phantom uncertainty	4.0	rectangular	$\sqrt{3}$	1	2.3%	∞
Liquid conductivity(target)	5.0	rectangular	$\sqrt{3}$	0.64	1.8%	∞
Liquid conductivity(meas.)	5.0	normal	1	0.64	3.2%	∞
Liquid permittivity(target)	5.0	rectangular	$\sqrt{3}$	0.6	1.7%	∞
Liquid permittivity(meas.)	5.0	normal	1	0.6	3.0%	∞

Uncertainty of SAR system

Combined Standard Uncertainty				10.6%	
Expanded Standard Uncertainty($k=2$)				20.6%	

Appendix D

Calibration Certificate

- PROBE

- DAE

- 835 MHz, 1900 MHz , 2450 MHz DIPOLE

- PROBE Calibration Certificate

Calibration Laboratory of
Schmid & Partner
Engineering AG
Zeughausstrasse 43, 8004 Zurich, Switzerland



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Accreditation No.: SCS 108

Client SGS KES (Dymstec)

Certificate No: ET3-1782_Apr07

CALIBRATION CERTIFICATE

Object	ET3DV6 - SN:1782					
Calibration procedure(s)	QA CAL-01,v5 and QA CAL-12,v4 Calibration procedure for dosimetric E-field probes					
Calibration date:	April 23, 2007					
Condition of the calibrated item	In Tolerance					
This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.						
All calibrations have been conducted in the closed laboratory facility: environment temperature $(22 \pm 3)^\circ\text{C}$ and humidity < 70%.						
Calibration Equipment used (M&TE critical for calibration)						
Primary Standards	ID #	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration			
Power meter E4419B	GB41293874	29-Mar-07 (METAS, No. 217-00670)	Mar-08			
Power sensor E4412A	MY41495277	29-Mar-07 (METAS, No. 217-00670)	Mar-08			
Power sensor E4412A	MY41498087	29-Mar-07 (METAS, No. 217-00670)	Mar-08			
Reference 3 dB Attenuator	SN: S5054 (3c)	10-Aug-06 (METAS, No. 217-00592)	Aug-07			
Reference 20 dB Attenuator	SN: S5086 (20b)	29-Mar-07 (METAS, No. 217-00671)	Mar-08			
Reference 30 dB Attenuator	SN: S5129 (30b)	10-Aug-06 (METAS, No. 217-00593)	Aug-07			
Reference Probe ES3DV2	SN: 3013	4-Jan-07 (SPEAG, No. ES3-3013_Jan07)	Jan-08			
DAE4	SN: 654	21-Jun-06 (SPEAG, No. DAE4-654_Jun06)	Jun-07			
Secondary Standards	ID #	Check Date (in house)	Scheduled Check			
RF generator HP 8648C	US3642U01700	4-Aug-99 (SPEAG, in house check Nov-05)	In house check: Nov-07			
Network Analyzer HP 8753E	US37390585	18-Oct-01 (SPEAG, in house check Oct-06)	In house check: Oct-07			
Calibrated by:	Name	Function	Signature			
	Katja Pokovic	Technical Manager				
Approved by:	Fin Bomhoff	R&D Director				
Issued: April 23, 2007						
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Glossary:

TSL	tissue simulating liquid
NORM x,y,z	sensitivity in free space
ConF	sensitivity in TSL / NORM x,y,z
DCP	diode compression point
Polarization ϕ	ϕ rotation around probe axis
Polarization θ	θ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., $\theta = 0$ is normal to probe axis

Calibration is Performed According to the Following Standards:

- a) IEEE Std 1528-2003, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", December 2003
- b) IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300 MHz to 3 GHz)", February 2005

Methods Applied and Interpretation of Parameters:

- $NORMx,y,z$: Assessed for E-field polarization $\theta = 0$ ($f \leq 900$ MHz in TEM-cell; $f > 1800$ MHz: R22 waveguide). $NORMx,y,z$ are only intermediate values, i.e., the uncertainties of $NORMx,y,z$ does not effect the E²-field uncertainty inside TSL (see below ConVF).
- $NORM(f)x,y,z = NORMx,y,z * frequency_response$ (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of ConVF.
- $DCPx,y,z$: DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency nor media.
- *ConVF and Boundary Effect Parameters*: Assessed in flat phantom using E-field (or Temperature Transfer Standard for $f \leq 800$ MHz) and inside waveguide using analytical field distributions based on power measurements for $f > 800$ MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to $NORMx,y,z * ConVF$ whereby the uncertainty corresponds to that given for ConVF. A frequency dependent ConVF is used in DASY version 4.4 and higher which allows extending the validity from ± 50 MHz to ± 100 MHz.
- *Spherical Isotropy (3D deviation from isotropy)*: In a field of low gradients realized using a flat phantom exposed by a patch antenna.
- *Sensor Offset*: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.

ET3DV6 SN:1782

April 23, 2007

Probe ET3DV6

SN:1782

Manufactured: April 15, 2003
Last calibrated: May 2, 2006
Recalibrated: April 23, 2007

Calibrated for DASY Systems

(Note: non-compatible with DASY2 system!)

ET3DV6 SN:1782

April 23, 2007

DASY - Parameters of Probe: ET3DV6 SN:1782**Sensitivity in Free Space^A**

NormX	2.02 ± 10.1%	µV/(V/m) ²	DCP X	92 mV
NormY	1.75 ± 10.1%	µV/(V/m) ²	DCP Y	93 mV
NormZ	1.75 ± 10.1%	µV/(V/m) ²	DCP Z	91 mV

Diode Compression^B**Sensitivity in Tissue Simulating Liquid (Conversion Factors)**

Please see Page 8.

Boundary Effect

TSL 900 MHz Typical SAR gradient: 5 % per mm

Sensor Center to Phantom Surface Distance	3.7 mm	4.7 mm
SAR _{be} [%] Without Correction Algorithm	8.9	4.6
SAR _{be} [%] With Correction Algorithm	0.1	0.2

TSL 1810 MHz Typical SAR gradient: 10 % per mm

Sensor Center to Phantom Surface Distance	3.7 mm	4.7 mm
SAR _{be} [%] Without Correction Algorithm	12.7	8.5
SAR _{be} [%] With Correction Algorithm	0.2	0.1

Sensor OffsetProbe Tip to Sensor Center **2.7** mm

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

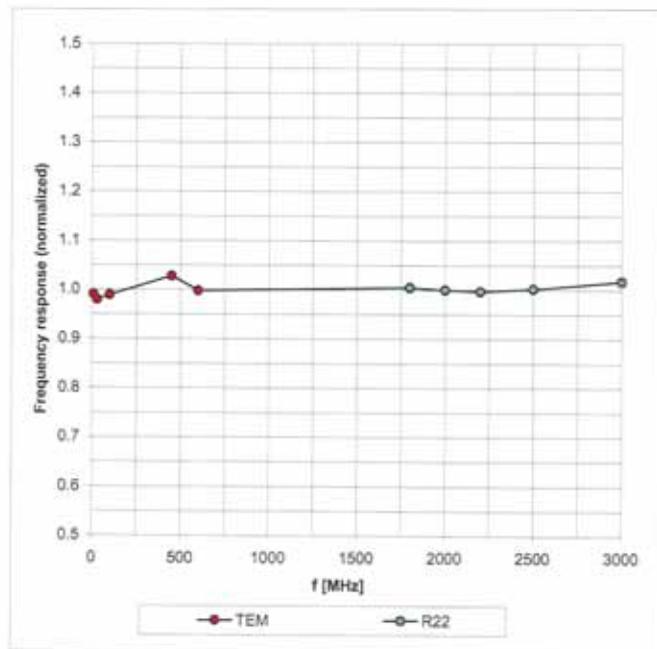
^A The uncertainties of NormX,Y,Z do not affect the E²-field uncertainty inside TSL (see Page 8).^B Numerical linearization parameter: uncertainty not required.

ET3DV6 SN:1782

April 23, 2007

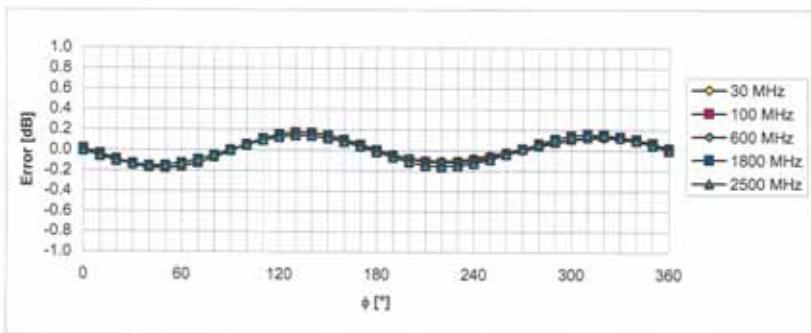
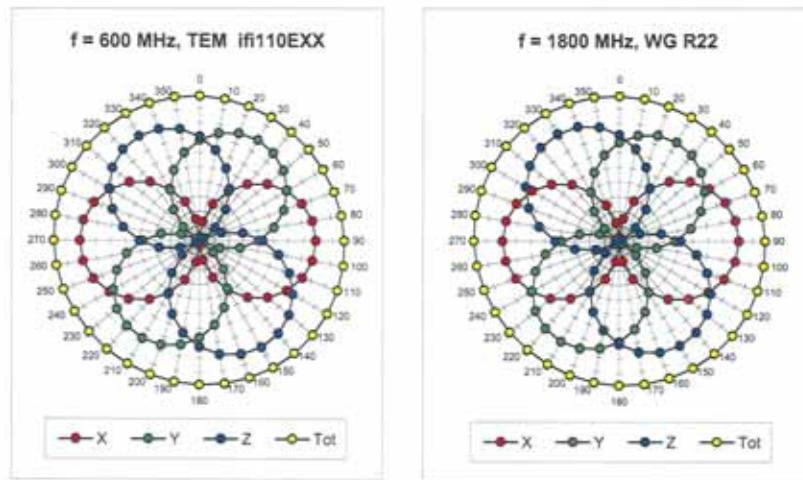
Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide: R22)

Uncertainty of Frequency Response of E-field: $\pm 6.3\%$ ($k=2$)

ET3DV6 SN:1782

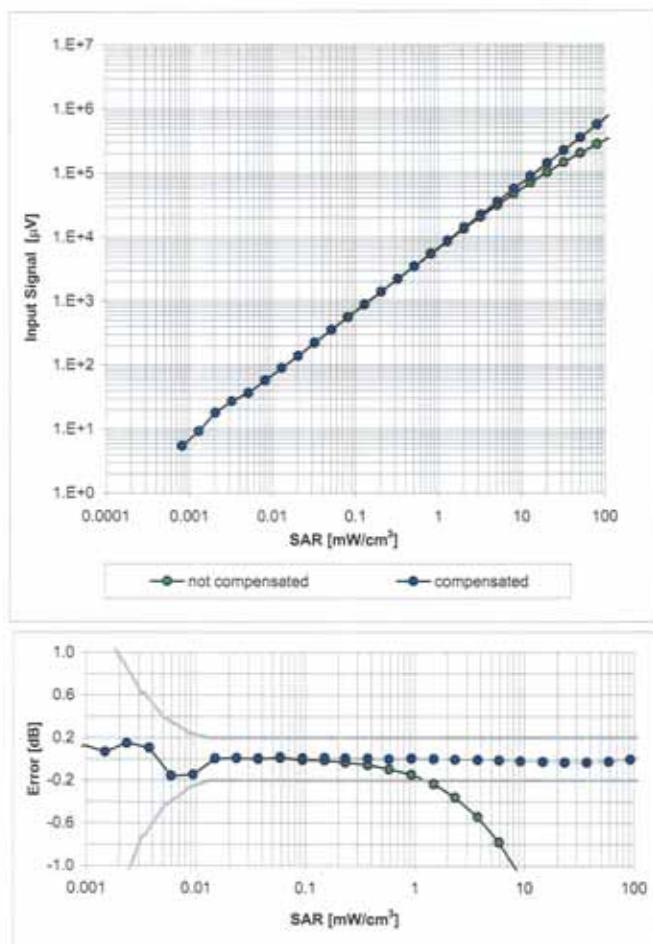
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Receiving Pattern (ϕ), $\theta = 0^\circ$ Uncertainty of Axial Isotropy Assessment: $\pm 0.5\%$ ($k=2$)

ET3DV6 SN:1782

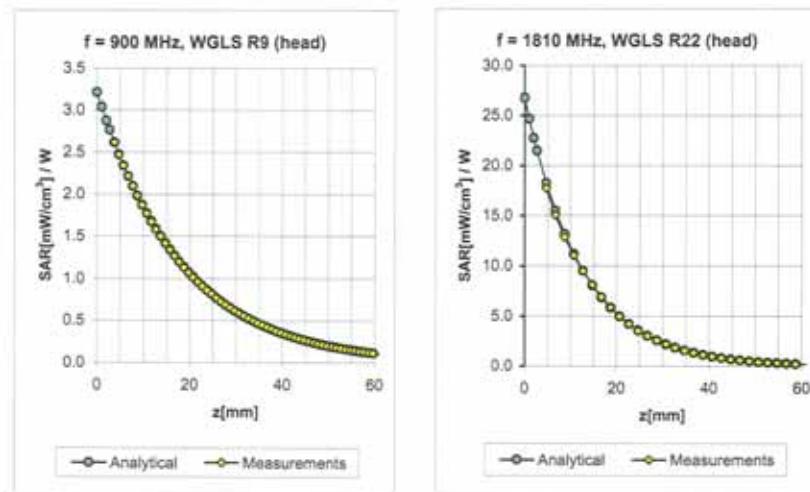
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Dynamic Range f(SAR_{head})
(Waveguide R22, f = 1800 MHz)

Uncertainty of Linearity Assessment: $\pm 0.6\%$ ($k=2$)

ET3DV6 SN:1782

April 23, 2007

Conversion Factor Assessment

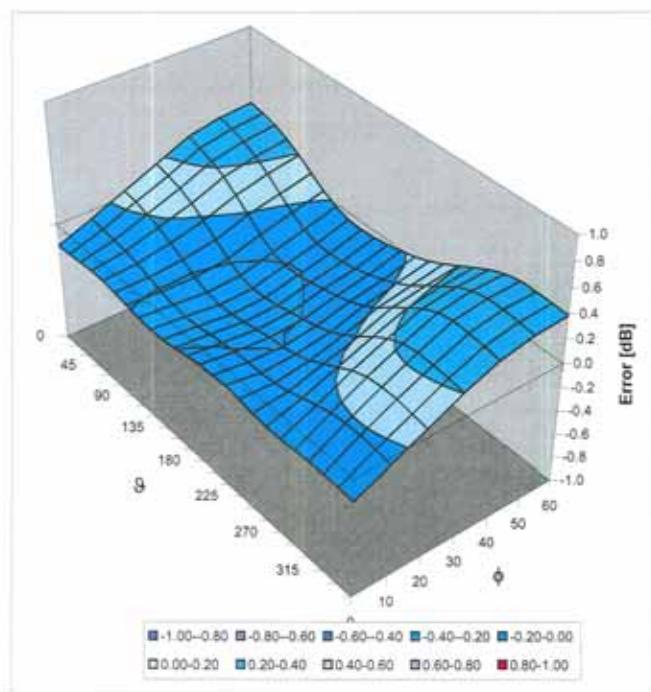
f [MHz]	Validity [MHz] ^c	TSL	Permittivity	Conductivity	Alpha	Depth	ConvF Uncertainty
450	$\pm 50 / \pm 100$	Head	$43.5 \pm 5\%$	$0.87 \pm 5\%$	0.40	1.93	$7.08 \pm 13.3\% (\text{k}=2)$
900	$\pm 50 / \pm 100$	Head	$41.5 \pm 5\%$	$0.97 \pm 5\%$	0.36	2.79	$6.18 \pm 11.0\% (\text{k}=2)$
1810	$\pm 50 / \pm 100$	Head	$40.0 \pm 5\%$	$1.40 \pm 5\%$	0.44	2.87	$5.16 \pm 11.0\% (\text{k}=2)$
2000	$\pm 50 / \pm 100$	Head	$40.0 \pm 5\%$	$1.40 \pm 5\%$	0.51	2.77	$4.82 \pm 11.0\% (\text{k}=2)$
2450	$\pm 50 / \pm 100$	Head	$39.2 \pm 5\%$	$1.80 \pm 5\%$	0.59	2.36	$4.62 \pm 11.8\% (\text{k}=2)$

450	$\pm 50 / \pm 100$	Body	$56.7 \pm 5\%$	$0.94 \pm 5\%$	0.33	1.93	$7.86 \pm 13.3\% (\text{k}=2)$
900	$\pm 50 / \pm 100$	Body	$55.0 \pm 5\%$	$1.05 \pm 5\%$	0.59	2.23	$5.96 \pm 11.0\% (\text{k}=2)$
1810	$\pm 50 / \pm 100$	Body	$53.3 \pm 5\%$	$1.52 \pm 5\%$	0.57	2.78	$4.84 \pm 11.0\% (\text{k}=2)$
2000	$\pm 50 / \pm 100$	Body	$53.3 \pm 5\%$	$1.52 \pm 5\%$	0.58	2.61	$4.51 \pm 11.0\% (\text{k}=2)$
2450	$\pm 50 / \pm 100$	Body	$52.7 \pm 5\%$	$1.95 \pm 5\%$	0.66	2.22	$4.14 \pm 11.8\% (\text{k}=2)$

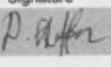
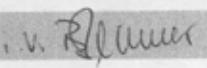
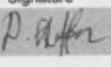
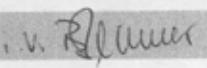
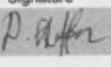
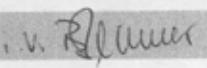
^c The validity of ± 100 MHz only applies for DASY v4.4 and higher (see Page 2). The uncertainty is the RSS of the ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band.

ET3DV6 SN:1782

April 23, 2007

Deviation from Isotropy in HSLError (ϕ, θ), $f = 900$ MHzUncertainty of Spherical Isotropy Assessment: $\pm 2.6\%$ ($k=2$)

-DAE Calibration Certificate

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<p>CALIBRATION CERTIFICATE</p> <table border="1"><tr><td>Object</td><td>DAE4 - SD 000 D04 BA - SN: 614</td></tr><tr><td>Calibration procedure(s)</td><td>QA CAL-06.v12 Calibration procedure for the data acquisition electronics (DAE)</td></tr><tr><td>Calibration date:</td><td>August 30, 2007</td></tr><tr><td>Condition of the calibrated item</td><td>In Tolerance</td></tr><tr><td colspan="2">This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.</td></tr><tr><td colspan="2">All calibrations have been conducted in the closed laboratory facility: environment temperature $(22 \pm 3)^\circ\text{C}$ and humidity < 70%.</td></tr><tr><td colspan="2">Calibration Equipment used (M&TE critical for calibration)</td></tr><tr><td>Primary Standards</td><td>ID #</td><td>Cal Date (Calibrated by, Certificate No.)</td><td>Scheduled Calibration</td></tr><tr><td>Fluke Process Calibrator Type 702</td><td>SN: 6295803</td><td>13-Oct-06 (Elcal AG, No: 5492)</td><td>Oct-07</td></tr><tr><td>Keithley Multimeter Type 2001</td><td>SN: 0810278</td><td>03-Oct-06 (Elcal AG, No: 5478)</td><td>Oct-07</td></tr><tr><td>Secondary Standards</td><td>ID #</td><td>Check Date (in house)</td><td>Scheduled Check</td></tr><tr><td>Calibrator Box V1.1</td><td>SE UMS 006 AB 1004</td><td>25-Jun-07 (SPEAG, in house check)</td><td>In house check Jun-08</td></tr><tr><td>Calibrated by:</td><td>Name Dominique Steffen</td><td>Function Technician</td><td>Signature </td></tr><tr><td>Approved by:</td><td>Fin Bomholt</td><td>R&D Director</td><td></td></tr><tr><td colspan="4">Issued: August 30, 2007</td></tr><tr><td colspan="4">This calibration certificate shall not be reproduced except in full without written approval of the laboratory.</td></tr></table>		Object	DAE4 - SD 000 D04 BA - SN: 614	Calibration procedure(s)	QA CAL-06.v12 Calibration procedure for the data acquisition electronics (DAE)	Calibration date:	August 30, 2007	Condition of the calibrated item	In Tolerance	This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.		All calibrations have been conducted in the closed laboratory facility: environment temperature $(22 \pm 3)^\circ\text{C}$ and humidity < 70%.		Calibration Equipment used (M&TE critical for calibration)		Primary Standards	ID #	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration	Fluke Process Calibrator Type 702	SN: 6295803	13-Oct-06 (Elcal AG, No: 5492)	Oct-07	Keithley Multimeter Type 2001	SN: 0810278	03-Oct-06 (Elcal AG, No: 5478)	Oct-07	Secondary Standards	ID #	Check Date (in house)	Scheduled Check	Calibrator Box V1.1	SE UMS 006 AB 1004	25-Jun-07 (SPEAG, in house check)	In house check Jun-08	Calibrated by:	Name Dominique Steffen	Function Technician	Signature 	Approved by:	Fin Bomholt	R&D Director		Issued: August 30, 2007				This calibration certificate shall not be reproduced except in full without written approval of the laboratory.			
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Glossary

DAE	data acquisition electronics
Connector angle	information used in DASY system to align probe sensor X to the robot coordinate system.

Methods Applied and Interpretation of Parameters

- *DC Voltage Measurement*: Calibration Factor assessed for use in DASY system by comparison with a calibrated instrument traceable to national standards. The figure given corresponds to the full scale range of the voltmeter in the respective range.
- *Connector angle*: The angle of the connector is assessed measuring the angle mechanically by a tool inserted. Uncertainty is not required.
- The following parameters contain technical information as a result from the performance test and require no uncertainty.
- *DC Voltage Measurement Linearity*: Verification of the Linearity at +10% and -10% of the nominal calibration voltage. Influence of offset voltage is included in this measurement.
- *Common mode sensitivity*: Influence of a positive or negative common mode voltage on the differential measurement.
- *Channel separation*: Influence of a voltage on the neighbor channels not subject to an input voltage.
- *AD Converter Values with inputs shorted*: Values on the internal AD converter corresponding to zero input voltage
- *Input Offset Measurement*: Output voltage and statistical results over a large number of zero voltage measurements.
- *Input Offset Current*: Typical value for information; Maximum channel input offset current, not considering the input resistance.
- *Input resistance*: DAE input resistance at the connector, during internal auto-zeroing and during measurement.
- *Low Battery Alarm Voltage*: Typical value for information. Below this voltage, a battery alarm signal is generated.
- *Power consumption*: Typical value for information. Supply currents in various operating modes.

DC Voltage Measurement

A/D - Converter Resolution nominal

High Range: 1LSB = $6.1\mu V$, full range = $-100...+300 mV$
Low Range: 1LSB = $61nV$, full range = $-1.....+3mV$

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

Calibration Factors	X	Y	Z
High Range	$403.926 \pm 0.1\% (k=2)$	$404.433 \pm 0.1\% (k=2)$	$405.056 \pm 0.1\% (k=2)$
Low Range	$3.95357 \pm 0.7\% (k=2)$	$3.93461 \pm 0.7\% (k=2)$	$4.00299 \pm 0.7\% (k=2)$

Connector Angle

Connector Angle to be used in DASY system	$231^\circ \pm 1^\circ$
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Appendix**1. DC Voltage Linearity**

High Range	Input (µV)	Reading (µV)	Error (%)
Channel X + Input	200000	200000	0.00
Channel X + Input	20000	20008.58	0.04
Channel X - Input	20000	-19999.47	0.00
Channel Y + Input	200000	200000.6	0.00
Channel Y + Input	20000	20007.85	0.04
Channel Y - Input	20000	-20001.41	0.01
Channel Z + Input	200000	199999.9	0.00
Channel Z + Input	20000	20006.37	0.03
Channel Z - Input	20000	-20004.86	0.02

Low Range	Input (µV)	Reading (µV)	Error (%)
Channel X + Input	2000	2000	0.00
Channel X + Input	200	199.76	-0.12
Channel X - Input	200	-199.68	-0.16
Channel Y + Input	2000	2000	0.00
Channel Y + Input	200	199.84	-0.08
Channel Y - Input	200	-200.52	0.26
Channel Z + Input	2000	2000	0.00
Channel Z + Input	200	199.27	-0.37
Channel Z - Input	200	-201.19	0.59

2. Common mode sensitivity

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	Common mode Input Voltage (mV)	High Range Average Reading (µV)	Low Range Average Reading (µV)
Channel X	200	1.30	0.67
	-200	-0.13	-0.60
Channel Y	200	8.11	7.55
	-200	-9.10	-9.60
Channel Z	200	-10.71	-10.45
	-200	9.01	8.76

3. Channel separation

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	Input Voltage (mV)	Channel X (µV)	Channel Y (µV)	Channel Z (µV)
Channel X	200	-	2.57	-0.89
Channel Y	200	0.47	-	4.63
Channel Z	200	-0.15	0.69	-

4. AD-Converter Values with inputs shorted

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	High Range (LSB)	Low Range (LSB)
Channel X	16227	16192
Channel Y	16375	15850
Channel Z	16067	15373

5. Input Offset Measurement

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

Input 10MΩ

	Average (µV)	min. Offset (µV)	max. Offset (µV)	Std. Deviation (µV)
Channel X	0.31	-0.54	1.27	0.41
Channel Y	-2.27	-3.06	-1.38	0.34
Channel Z	-0.93	-2.53	0.20	0.41

6. Input Offset Current

Nominal Input circuitry offset current on all channels: <25fA

7. Input Resistance

	Zeroing (MOhm)	Measuring (MOhm)
Channel X	0.2000	196.9
Channel Y	0.2000	200.7
Channel Z	0.2000	202.1

8. Low Battery Alarm Voltage (verified during pre test)

Typical values	Alarm Level (VDC)
Supply (+ Vcc)	+7.9
Supply (- Vcc)	-7.6

9. Power Consumption (verified during pre test)

Typical values	Switched off (mA)	Stand by (mA)	Transmitting (mA)
Supply (+ Vcc)	+0.0	+6	+14
Supply (- Vcc)	-0.01	-8	-9